PCN Number: 2023			230522002.1		PCN	Date:	May 24, 2023			
Title: Qualification of RF. select devices			AB	as an add	itional Fab s	ite opti	on an	d new A	ssembly site (MLA) for	
<b>Customer Contact:</b>			PCN Manager		Dept:		Quality Services			
Proposed 1 <sup>st</sup> Ship Date:					ample requests accepted until:		Jun 24, 2023*			
*Sample requests received				after Jun 24, 2023 will not be supported.						
Change Type:										
	nbly Site		$\boxtimes$	Assembly Process		Σ	Asse	Assembly Materials		
□ Design □	n			☐ Electrical Specification		ion		Mec	Mechanical Specification	
☐ Test S	Site			☐ Packing/Shipping/Labeling		abeling		Test	Test Process	
Wafer	Bump Site			☐ Wafer Bump Material			Waf	Wafer Bump Process		
	Fab Site		₩afer Fab Materials		5		☑ Waf	Wafer Fab Process		
			☐ Part number change			•				
				P	<b>CN</b> Detai	ls				

## **Description of Change:**

Texas Instruments is pleased to announce the qualification of its RFAB fabrication facility as an additional Wafer Fab option in addition to new Assembly site for the devices listed in the "Product Affected" section.

Cu	rrent Fab	Site	Additional Fab site		
Current Fab Site	Process	Wafer Diameter	Additional Fab site	Process	Wafer Diameter
GFAB6/8	P2CMOS	150/200mm	RFAB	LBC9	300mm
DFAB	FZCMU3	200mm	KFAD	LDC9	300111111

Construction differences and AT site options are as follows:

	TIEMA	AP1	MLA
Bond wire composition, diameter diameter	Cu, 0.96 or Au, 0.9 mil	Au, 1.0 mil	Cu, 0.8 mil
Lead Finish	Matte Sn	Matte Sn	NiPdAui
Mount Compound	4213245	SID#101375281	4147858
Mold Compound	8095179	SID#101380756	4211880
Marking	NS-D8	NS-D8	8D-TI-PIN1DOT

# Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

## Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

# **Impact on Environmental Ratings**

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

	en Status IEC 62474
No Change	hange 🛛 No Change

## Changes to product identification resulting from this PCN:

## **Fab Site Information:**

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
DFAB	DLN	USA	Dallas
GFAB6	GF6	GBR	Greenock
GFAB8	GF8	GBR	Greenock
RFAB	RFB	USA	Richardson

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
AP1	AKR	PHL	Cupang, Muntinlupa City
TIEMA	CU6	MYS	Melaka
MLA	MLA	MYS	Kuala Lumpur

#### Die Rev:

Current New

Die Rev [2P]	Die Rev [2P]
С	C

Sample product shipping label (not actual product label):



MADE IN: Malaysia 2DC: 2Q:

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

(L)T0:3750



(1P) SN74LS07NSR

(Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(2P) REV: (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

## **Product Affected:**

LINCO/ 02AINA/NOFD	LMC6762AIMX	IX/NOPB LMC6762BI	MX/NOPB LMC6772A	AIMX/NOPB LMC6772B	IMX/NOPB	
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#### Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: LMC6762AIMX/NOPB	Qual Device: LMC6772AIMX/NOPB	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: OPA2991QDRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	1/77/0	-	-	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	1/77/0	-	-	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0
HTSL	A6	High Temperature Storage Life	175C	500 Hours	1/77/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-
HTOL	B1	Life Test	150C	300 Hours	1/77/0	-	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-
ESD	E2	ESD CDM	-	500 Volts	1/3/0	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	1/3/0	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	1/6/0	1/6/0	-	-
LU	E4	Latch-Up	Per JESD78	-	1/6/0	1/6/0	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	3/90/0	-	-	-

- QBS: Qual By Similarity
- Qual Device LMC6762AIMX/NOPB is qualified at MSL1 260C
- Qual Device LMC6772AIMX/NOPBis qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

### Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2302-035

For questions regarding this notice, e-mails can be sent to the contact shown below or your local Field Sales Representative.

Location	E-Mail			
WW Change Management Team	PCN ww admin team@list.ti.com			

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